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Notice of Allowability	Application No.	Applicant(s)	
	09/695,726	LEE, SHING M.	
	Examiner	Art Unit	
	Kalimah Fernandez	2881	
The MAILING DATE of this communication appears on the cover sheet with the correspondence address All claims being allowable, PROSECUTION ON THE MERITS IS (OR REMAINS) CLOSED in this application. If not included herewith (or previously mailed), a Notice of Allowance (PTOL-85) or other appropriate communication will be mailed in due course. THIS NOTICE OF ALLOWABILITY IS NOT A GRANT OF PATENT RIGHTS. This application is subject to withdrawal from issue at the initiative of the Office or upon petition by the applicant. See 37 CFR 1.313 and MPEP 1308.			
1. This communication is responsive to <u>5-14-04</u> .			
2. The allowed claim(s) is/are 1,2,4,7-9,11,12,14,16,18,22,23,32,34-41 and 43-48.			
3. The drawings filed on 15 October 2002 are accepted by the Examiner.			
<ul> <li>4. Acknowledgment is made of a claim for foreign priority under 35 U.S.C. § 119(a)-(d) or (f).</li> <li>a) All b) Some* c) None of the: <ol> <li>Certified copies of the priority documents have been received.</li> <li>Certified copies of the priority documents have been received in Application No.</li> <li>Copies of the certified copies of the priority documents have been received in this national stage application from the International Bureau (PCT Rule 17.2(a)).</li> </ol> </li> <li>* Certified copies not received:</li> </ul>			
Applicant has THREE MONTHS FROM THE "MAILING DATE" of this communication to file a reply complying with the requirements noted below. Failure to timely comply will result in ABANDONMENT of this application.  THIS THREE-MONTH PERIOD IS NOT EXTENDABLE.			
<ol> <li>A SUBSTITUTE OATH OR DECLARATION must be submitted. Note the attached EXAMINER'S AMENDMENT or NOTICE OF INFORMAL PATENT APPLICATION (PTO-152) which gives reason(s) why the oath or declaration is deficient.</li> </ol>			
<ul> <li>6. CORRECTED DRAWINGS (as "replacement sheets") must be submitted.</li> <li>(a) including changes required by the Notice of Draftsperson's Patent Drawing Review (PTO-948) attached</li> <li>1) hereto or 2) to Paper No./Mail Date</li> <li>(b) including changes required by the attached Examiner's Amendment / Comment or in the Office action of Paper No./Mail Date</li> <li>Identifying indicia such as the application number (see 37 CFR 1.84(c)) should be written on the drawings in the front (not the back) of each sheet. Replacement sheet(s) should be labeled as such in the header according to 37 CFR 1.121(d).</li> </ul>			
7. DEPOSIT OF and/or INFORMATION about the deposit of BIOLOGICAL MATERIAL must be submitted. Note the attached Examiner's comment regarding REQUIREMENT FOR THE DEPOSIT OF BIOLOGICAL MATERIAL.			
Attachment(s)  1. ☐ Notice of References Cited (PTO-892)  2. ☐ Notice of Draftperson's Patent Drawing Review (PTO-948)  3. ☐ Information Disclosure Statements (PTO-1449 or PTO/SB/0 Paper No./Mail Date  4. ☐ Examiner's Comment Regarding Requirement for Deposit of Biological Material	5. Notice of Informal P 6. Interview Summary Paper No./Mail Dat 7. Examiner's Amendr 8. Examiner's Stateme 9. Other	(PTO-413), te nent/Comment	

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## **DETAILED ACTION**

## Allowable Subject Matter

- 1. Claims 1-2,4,7-9,11-12,14,16,18,22-23,32,34-41, and 43-48 are allowed. The following is an examiner's statement of reasons for allowance: the prior art of record fails to teach or obviously suggest the claimed invention.
- 2. Specifically, no teaching or obvious suggestion was found of the limitation " at least a first and a second wavelength dispersive x-ray detector positioned above the sample wherein each detector detects X-rays about a different characteristic emission level, wherein the first detector is configured to detect X-rays having characteristic emission levels for a top layer of the film stack and second detector is configured to detect X-rays having characteristic emission levels for an underlying layer that lies beneath the top layer, whereby material characteristics of the desired layers can be measured simultaneously" in combination with the other recited limitations of claims 1 and 11.
- 3. Similarly, no teaching or obvious suggestion was found of the limitation " at least a first and a second wavelength dispersive X-ray detector positioned above the sample wherein each detector is configured

to detect a respective portion of the X-rays emanating from the sample, whereby material characteristics of the at least two layers can be measured simultaneously" in combination with the other recited limitations of claim 37.

4. Claims 2,4,7-9,12,14,16,18,22-23,32,34-36,38-41, and 43-48 are allowed by virtue of their dependency.

Any comments considered necessary by applicant must be submitted no later than the payment of the issue fee and, to avoid processing delays, should preferably accompany the issue fee. Such submissions should be clearly labeled "Comments on Statement of Reasons for Allowance."

## Conclusion

Any inquiry concerning this communication or earlier communications from the examiner should be directed to Kalimah Fernandez whose telephone number is 571-272-2420. The examiner can normally be reached on Mon-Tues 6:30-3:30; Wed-Thurs 8-5 and Fri.9am-6 pm.

If attempts to reach the examiner by telephone are unsuccessful, the examiner's supervisor, John R Lee can be reached on 571-272-2477. The fax phone number for the organization where this application or proceeding is assigned is 703-872-9306.

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Information regarding the status of an application may be obtained from the Patent Application Information Retrieval (PAIR) system. Status information for published applications may be obtained from either Private PAIR or Public PAIR. Status information for unpublished applications is available through Private PAIR only. For more information about the PAIR system, see http://pair-direct.uspto.gov. Should you have questions on access to the Private PAIR system, contact the Electronic Business Center (EBC) at 866-217-9197 (toll-free).

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JOHN R. LEE

SUPERVISORY PATENT EXAMINER
AECHNOLOGY CENTER 2800